

**Notice of References Cited**

Application/Control No. <b>10/084,616</b>	Applicant(s)/Patent Under Reexam <b>Detwiler et al.</b>	
Examiner <b>Hilary Gutman</b>	Art Unit <b>3612</b>	Page 1 of 1

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**NON-PATENT DOCUMENTS**

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